

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

2684

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,317,609 ✓	11-2001	Alperovich et al.	455/556
	B	US-6,128,509 ✓	10-2000	Veijola et al.	455/556
	C	US-6,128,446 ✓	10-2000	Schrock et al.	396/297
	D	US-5,737,491 ✓	04-1998	Allen et al.	704/270
	E	US-6,337,712 ✓	01-2002	Shiota et al.	348/231.1
	F	US-6,085,112 ✓	07-2000	Kleinschmidt et al.	455/556
	G	US-6,434,403 ✓	08-2002	Ausems et al.	455/556
	H	US-6,424,843 ✓	07-2002	Reitmaa et al.	455/566
	I	US-6,219,560 ✓	04-2001	Erkkila et al.	455/557
	J	US-6,374,082 ✓	04-2002	Carlson, Grant B.	455/63
	K	US-6,201,975 ✓	03-2001	Isberg et al.	455/557
	L	US-6,038,295 ✓	03-2000	Mattes, Heinz	379/93.25
	M	US-6,349,324 ✓	02-2002	Tokoro, Mario	709/200

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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